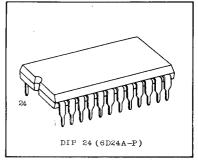
TC4036BP, TC4039BP

TC4036BP 4 WORD × 8 BIT STATIC RAM (BINARY ADDRESSING)
TC4039BP 4 WORD × 8 BIT STATIC RAM (DIRECT WORD-LINE ADDRESSING)

TC4036BP/TC4039BP are static RAM of 4×8 bits and since eight data input/output lines are mutually independently provided for one word, wide variety of applications are expected for scratch pad memories, channel preset memories of digital frequency synthesizer systems, etc.

 $TC4036BP\$ Each word is binarily selected by two lines of address inputs A_0 and $A_1.$

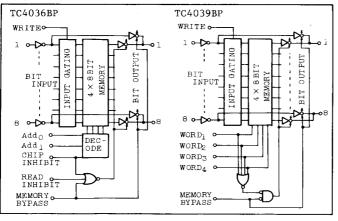
 ${\rm TC4039BP}$ Each word is directly selected by mutually independent four lines of address inputs WORD 1 through WORD 4.



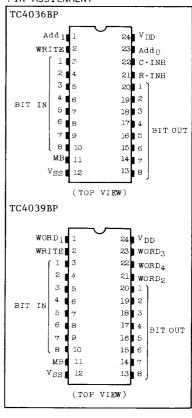
ABSOLUTE MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	RATING	UNIT
DC Supply Voltage	v_{DD}	$V_{SS}-0.5 \sim V_{SS}+20$	V
Input Voltage	VIN	$V_{SS}-0.5 \sim V_{DD}+0.5$	V
Output Voltage	V _{OUT}	$V_{SS}-0.5 \sim V_{DD}+0.5$	V
DC Input Current	IIN	±10	mA
Power Dissipation	P_{D}	300	mW
Operating Temperature Range	T_{A}	- 40 ∼ 85	°C
Storage Temperature Range	T _{stg}	- 65 ∼ 150	°C
Lead Temp./Time	Tso1	260°C · 10 sec	

BLOCK DIAGRAM



PIN ASSIGNMENT



FUNCTION TABLE

TC4036	ВP									
WRITE	READ INHIBIT	MEMORY BYPASS	CHIP INHIBIT	OPERATIONAL MODEL						
*	*	L	Н	Each bit output has high impedance generating floati condition. Writing into the memory is not performed						
*	*	Н	H	Bit input data is directly output to the corresponding bit output. The memory retains the content of bit						
L	*	H	L	input data written in previous write mode.						
Н	*	Н	L	Bit input data is directly output to the corresponding bit output. But input data is written into the word memory designated by address inputs AO and A1.						
L	L	L	L	Memory data is read from the word designated by addres inputs A_0 and A_1 . Writing into the memory is not performed.						
L	Н	L	L	Each bit output has high impedance generating floating condition. Writing into the memory is not performed.						
Н	L	L	L	As well as each bit input data is written into the word memory designated by address inputs AO and A1, the input data is read out.						
Н	Н	L	L	Each bit output has high impedance generating floating condition. Each bit input data is written into the word memory designated by address inputs AO and A1.						
TC4039	ВР	<u> </u>								
WRITE	MEMORY BYPASS	WORD1 ~ WORD4		OPERATIONAL MODE						
*	L	all L	condition	output has high impedance generating floating on. The memory retains the content of bit input data in previous write mode.						
*	Н	all L	Bit inpu	ut data is directly output to the corresponding bit The memory retains the content of bit input data						
L	Н	_	written	in previous write mode.						
н	Н		Bit input data is directly output to the corresponding bit output. Each bit input data is written into the memory designated by the word input.							
L	L		into the	lata designated by the word input is read out. Writing memory is not performed.						
Н	L		As well as each bit input data is written into the memory designated by the word input, the input data is read out.							

ADDRESS TRUTH TABLE

гс4036вР	•	
Add1	Add0	ADDRESSED WORD
L	L	WORD 1
L	Н	WORD 2
Н	L	WORD 3
Н	Н	WORD 4

TC403 9 BP	•								
WORD 1	WORD 2	WORD 3	WORD 4	ADDRESSED WORD					
Н	L	L	L	WORD 1					
L	Н	L	L	WORD 2					
L	L	Н	L	WORD 3					
L	L	L	Н	WORD 4					
L	L	L	L	NONE					
	OTHER	STATES		*					
* Inhibit mode									

RECOMMENDED OPERATING CONDITIONS (VSS=0V)

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT
DC Supply Voltage	v_{DD}	3		18	v
Input Voltage	VIN	0	-	$v_{ m DD}$	V

STATIC ELECTRICAL CHARACTERISTICS (Vss=0V)

CHARACTERISTIC	SYM-	TEST CONDITION	$v_{ m DD}$	-40°C		25°C			85°	UNIT	
CHARACTERISTIC	BOL	TEST CONDITION	(V)	MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.	UNII
] I _{OUT}] <1 µA	5	4.95	-	4.95	5.00	-	4.95	-	
High-Level Output Voltage	VOH	V _{IN} =V _{SS} , V _{DD}	10	9.95	-	9.95	10.00	-	9.95	-	
		114 507 50	15	14.95	-	14.95	15.00	-	14.95	-	
		I _{OUT} < 1 µA	5	-	0.05	-	0.00	0.05	-	0.05	V
Low-Level Output Voltage	VOL	V _{IN} =V _{SS} ,V _{DD}	10	-	0.05	-	0.00	0.05	- ;	0.05	
		111 003 00	15	-	0.05	- 1	0.00	0.05	-	0.05	
		V _{OH} =4.6V	5	-0.61	-	-0.51	-1.0	-	-0.42	-	
	IOH	V _{OH} =2.5V	5	-2.5	-	-2.1	-4.0	_	-1.7	-	
Output High Current		V _{OH} =9.5V	10	-1.5	-	-1.3	-2.2	_	-1.1	-	
		V _{OH} =13.5V	15	-4.0	_	-3.4	-9.0	_	-2.8	-	
		$v_{IN}=v_{SS}, v_{DD}$			•						
		V _{OL} =0.4V	5	0.61	-	0.51	1.5	-	0.42	_	mA
Output Low	IOL	V _{OL} =0.5V	10	1.5	-	1.3	3.8	-	1.1	-	
Current	-01	V _{OL} =1.5V	15	4.0	-	3.4	15.0	-	2.8	-	
		V _{IN} =V _{SS} ,V _{DD}									

STATIC ELECTRICAL CHARACTERISTICS (VSS=0V)

CHARACTERISTIC SYN			- TEST CONDITION		V _{DD} -40°C			25°C		85°C		UNIT
BO		BOL	TEST CONDITION	(V)	MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.	
			V _{OUT} =0.5V, 4.5V	5	3.5	_	3.5	2.75	-	3.5	_	
Input High	ι .	VIH	V _{OUT} =1.0V, 9.0V	10	7.0	-	7.0	5.5	-	7.0	-	
Voltage		\ \1H	V _{OUT} =1.5V,13.5V	15	11.0	-	11.0	8.25	-	11.0	_	
			I _{OUT} < 1 \(\mu \)A									v
			V _{OUT} =0.5V, 4.5V	5	-	1.5	-	2.25	1.5	-	1.5	V
Input Low		VIL	V _{OUT} =1.0V, 9.0V	10	-	3.0	-	4.5	3.0	_	3.0	
Voltage		1,17	V _{OUT} =1.5V,13.5V	15	-	4.0	-	6.75	4.0	-	4.0	
			I _{OUT} <1µA									
Input	"H" Level	IIH	V _{IH} =18V	18	-	0.1	_	10-5	0.1	-	1.0	μA
Current	"L" Level	ı _{IL}	VIT=0A	18	-	-0.1	-	-10-5	-0.1	_	-1.0	1
3-State Output	"H" Level	IDH	V _{OUT} =18V	18	_	0.4	-	10-4	0.4	-	12	μA
Leakage Current	"L" Level	I _{DL}	V _{OUT} =0V	18	_	-0.4	_	-10-4	-0.4	_	-12	
	.1	1		5		5	-	0.005	5		150	
Quiescent Current	Device	vice $ _{I_{ m DD}}$	V _{IN} =V _{SS} ,V _{DD}	10	-	10	-	0.010	10	-	300	μА
Current			*	15		20	-	0.015	20	_	600	

^{*} All valid input combinations.

DYNAMIC ELECTRICAL CHARACTERISTICS (Ta=25°C, $V_{\rm SS}$ =0V, $C_{\rm L}$ =50pF)

CHARACTERISTIC	SYMBOL	TEST CONDITION	V _{DD} (V)	MIN.	TYP.	MAX.	UNIT
Output Transition Time			5	_	80	200	
	tTLH		10	-	50	100	
(Low to High)			15	-	40	80	
Output Transition Time (High to Low)			5	_	80	200	ns
	tTHL		10	'	50	100	
			15	-	40	80	

DYNAMIC ELECTRICAL CHARACTERISTICS (Ta=25°C, $V_{SS}=0V$, $C_L=50pF$)

DINAMIC ELECTRICAL CHARA		165 (1a=25 C, Vg	3 01, 01,	Jopr)		f	
CHARACTERISTIC	SYMBOL	TEST CONDITION	V _{DD} (V)	MIN.	TYP.	MAX.	UNIT
Propagation Delay Time	t_{pZL}		5	_	200	750	
(R·INH - BIT OUT)	tpZH	R _L =1kΩ	10	-	90	350	ns
(TC4036BP)	PLII		15	_	70	300	
Propagation Delay Time	tpZL		5	-	250	750	
(C·INH - BIT OUT)	tpZH	R _L =1kΩ	10	-	120	350	ns
(TC4036BP)	P3		15		90	300	
Propagation Delay Time	t _{pLH}		5	-	210	750	
(M·B - BIT OUT)	t _{pHL}		10	-	100	350	ns
	F		15	-	80	300	
Propagation Delay Time	$t_{ m pLH}$		5	_	260	75Q	
(Add.WORD - BIT OUT)	tpHL		10	-	110	350	ns
	•		15	_	80	300	
Min. Set-up Time			5	-	45	200	
(Add. WORD - WRITE)	tsu		10	-	25	110	ns
			15	-	20	60	
Min. Hold Time			5	_	-60	100	
(Add. WORD - WRITE)	t _H		10	-	-35	70	ns
			15	-	-25	40	
Min. Pulse Width			5	-	60	150	
(WRITE)	t _{WH}		10	-	20	60	ns
			15	-	15	50	
Min. Set-up Time			5	_	-20	100	
(BIT IN - WRITE)	t _{SU}		10	-	-15	50	ns
			15	-	-10	40	
Min. Hold Time			5	- ;	40	200	-
(BIT IN - WRITE)	t _H		10	-	25	90	ns
(= = ==: <u>,</u>			15	_	20	60	
Input Capacitance	CIN	1		-	5	7.5	pF

